## Notice of References Cited Application/Control No. 10/635,364 Examiner Derek S. Chapel Applicant(s)/Patent Under Reexamination MEI ET AL. Art Unit Page 1 of 1

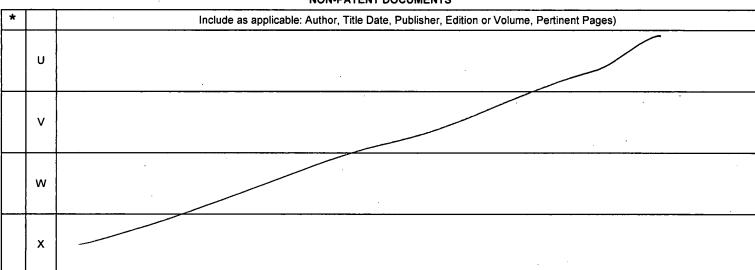
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.